STS8200 PMOS Power Discrete Test System



System Features

- Focus on high power discrete test, including MOSFET, IGBT, SiC MOSFET, Diode
- Multi-Task Test mode support DC, UIS. DVDS, Cg/Rg and Dynamic switching testing at the same time
 - -Up to ±2000V/±200A for DC test, 3000V is optional
 - -Up to 200A/2000V
 - -Up to 55V/40A(Max power to 900W) for DVDS test
 - -Support Cg/Rg test, AC frequency range: 100K-1MHz, DC bias default to 40V, can upgraded to 2000V
 - -Up to 1200V/800A for dynamic switching test.
- Menu Driven Programming
- Flexible expansion to Analog IC tester or mixed signal IC tester under CROSS mainframe

Resource	Specification
SVI40	• Super V/I, independent V/Is for discrete DC test, up to ±50V/±40A
HVS2K	High voltage source, up to ±2000V/±10mA
HCB200	High current source, up to ±200A pulsed
DC Test Box	DC test box with low Rdson and low leakage test module inside
UIS100	• Independent UIS test kit, up to 100A/2000V(Max 2000V@RH55%)
UIS200	Independent UIS test kit, up to 200A/2000V
DVX300	DVX test board within 50V/10A/300W/100mS
DVX900	DVX test board within 55V/40A/900W/9.99S
ZMU	• Support Cg/Rg test, AC frequency 100K-1MHz, DC bias default to ±40V, can upgrade to 2000V
DSU1200	• 1200V/800A Dynamic Switching Test Unit, support double/multiple switching test and short circuit current.

Note: Subject to change without notice.

